TOSHIBA Photocoupler IRED & Photo IC

6N138, 6N139

Current Loop Driver Low Input Current Line Receiver CMOS Logic Interface

The TOSHIBA 6N138 and 6N139 consists of an infrared emitting diode coupled with a split-Darlington output configuration.

A high speed Ired manufactured with an unique LPE junction, has the virtue of fast rise and fall time at low drive current.

- Isolation voltage: 2500 Vrms (min)
- · Current transfer ratio

: 6N138 - 300% (min) (IF=1.6mA)

: 6N139 - 400% (min) (IF=0.5mA)

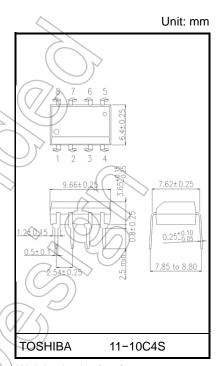
Switching time: 6N138 - tPHL = 10µs (max)

- tPLH = 35 μ s (max)

 $6N139 - tPHL = 1\mu s (max)$

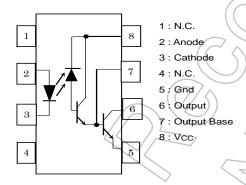
- tpl $H = 7\mu s (max)$

• UL-recognized: UL 1577, File No.E67349

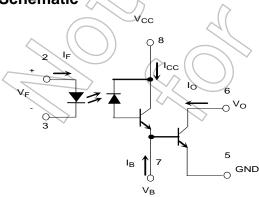


Weight: 0.54 g (typ.)

Pin Configuration (top view)







Start of commercial production 1988-02



Absolute Maximum Ratings (*) (Ta = 0°C to + 70°C)

Characteristics			Symbol	Rating	Unit	
LED	Forward current	(Note 1)	lF	20	mA	
	Pulse forward current		IFP ^(*1)	40	mA	
	Total pulse forward current		IFP ^(*2)	1	A	
	Reverse voltage		VR	5	V	
	Diode power dissipation	(Note 2)	PD	35	(MW)	
	Output current	(Note 3)	lo	60	mA	
Detector	Emitter-base reverse voltage		VEB	0.5		
	Supply voltage		VCC(*3)	-0.5 to 18	V	
	Output voltage		AO _(*3)	-0.5 to 18)) v	
	Output power dissipation	(Note 4)	Po	100	mW	
Operating temperature range			Topr	0 to 70	°C	
Storage temperature range			T _{stg}	-55 to 125 °C		
Lead solder temperature (10s) (*4)			T _{sol}	260	O CC	
Isolation voltage (60s, R.H.≤ 60%)		BVs ^(**) 2500 3540		Vrms		

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc.).

- (*) JEDEC registered data
- (**) Not registered JEDEC
- (*1) 50 % duty cycle, 1 ms pulse width
- (*2) Pulse width 1 µs, 300 pps
- (*3) 6N138··· -0.5 to 7 V
- (*4) 1.6 mm below seating plane



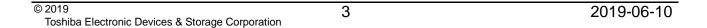


Electrical Characteristics

Over Recommended Temperature (Ta = 0°C to 70°C, unless otherwise noted)

Characteristics		Symbol	Test Condition	Min	(*5)Typ.	Max	Unit
Current transfer	6N139	CTR(*)	I _F = 0.5 mA, V _O = 0.4 V V _{CC} = 4.5 V	400	800	_	· %
ratio (Note 5, 6)			IF = 1.6 mA, V _O = 0.4 V V _{CC} = 4.5V	500	900	_	
	6N138			300	600	_	
	6N139	VoL	I _F = 1.6 mA, I _O = 6.4 mA V _{CC} = 4.5 V	77/1	0.1	0.4	. V
Logic low output			I _F = 5 mA, I _O = 15 mA V _{CC} = 4.5 V)) _	0.1	0.4	
voltage (Note 6)			I _F = 12 mA, I _O = 24 mA V _{CC} = 4.5 V)/_	0.2	0.4	
	6N138		I _F = 1.6 mA, I _O = 4.8 mA V _{CC} = 4.5 V	_	0.1	0.4	
Logic high output	6N139	- I _{OH} (*)	IF = 0 mA, V _O = V _{CC} = 18 V	_ (0.05	100	μА
current (Note 6)	6N138		$I_F = 0 \text{ mA}, V_O = V_{CC} = 7 \text{ V}$		0.05	250	
Logic low supply current	(Note 6)	ICCL	I _F = 1.6 mA, V _O = Open V _{CC} = 5 V		0.2	_	mA
Logic high supply current	(Note 6)	Іссн	I _F = 0 mA, V _O = Open, V _{CC} = 5 V		10	_	nA
Input forward voltage			I _F = 1.6 mA, Ta = 25 °C)+	1.65	1.7	V
Input reverse breakdown voltage BV _R (*)			I _R = 10 μA, Ta = 25 °C	5	_	_	V
Temperature coefficient of forward voltage ΔV _F /ΔTa			lF ≥ 1.6 mA	_	-1.9	_	mV / °C
Input capacitance C _{IN}			f = 1 MHz, V _F = 0 V	_	60	_	pF
Resistance (input-output)	RI-O	V _{I-O} = 500 V R.H.≤ 60 % (Note 7),		10 ¹²		Ω	
Capacitance (input-output)		CI/O	f = 1 MHz, V = 0 V (Note 7)	_	0.6	_	pF

^(**) JEDEC registered data.



^(*5) All typical values are at Ta = 25 °C and Vcc = 5 V, unless otherwise noted.



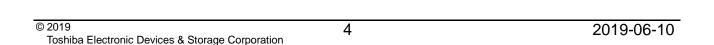
Switching Specifications (Ta=25°C, Vcc=5V, unless otherwise specified)

Characteristics		Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Propagation delay	6N139	tpHL(*)	1	IF = 0.5 mA, $R_L = 4.7 \text{ k}\Omega$		5	25	μS
time to logic low				I_F = 12 mA, R_L = 270 $Ω$	_	0.2	1	
at output (Note 6, 8)	6N138			$I_F = 1.6$ mA, $R_L = 2.2$ kΩ	7	1	10	
Propagation delay	6N139			$I_F = 0.5 \text{ mA}, R_L = 4.7 \text{ k}\Omega$		5	60	
time to logic high		t _{pLH} (*)	1	I_F = 12 mA, R_L = 270 $Ω$	H) Y	7	μS
at output (Note 6, 8)	6N138			I_F = 1.6 mA, R_L = 2.2 kΩ	7/4	4	35	
Common mode transient immunity at logic high level output	(Note 9)	СМН	2	$I_F = 0 \text{ mA}, R_L = 2.2 \text{ k}\Omega$ $V_{CM} = 400 \text{ V}_{p-p}$	<u>)</u> >	500	_	V / μs
Common mode transient immunity at logic low level output	(Note 9)	CML	2	$I_{F} = 1.6 \text{ mA} \\ R_{L} = 2.2 \text{ k}\Omega \\ V_{CM} = 400 \text{ V}_{p-p}$		-500	1//	V / μs

(*)JEDEC registered data.

- (Note 1): Derate linearly above 50 °C free—air temperature at a rate of 0.4 mA / °C
- (Note 2): Derate linearly above 50 °C free—air temperature at a rate of 0.7 mW / °C
- (Note 3): Derate linearly above 25 °C free—air temperature at a rate of 0.7 mA / °C
- (Note 4): Derate linearly above 25 °C free-air temperature at a rate of 2.0 mW / °C
- (Note 5): DC CURRENT TRANSFER RATIO is defined as the ratio of output collector current, Io, to the forward LED input current, IF, times 100 %.
- (Note 6): Pin 7 open.
- (Note 7): Device considered a two–terminal device: Pins 1, 2, 3, and 4 shorted together and Pins 5, 6, 7 and 8 shorted together.
- (Note 8): Use of a resistor between pin 5 and 7 will decrease gain and delay time.
- (Note 9): Common mode transient immunity in logic high level is the maximum tolerable (positive) dVCM / dt on the leading edge of the common mode pulse, VCM, to assure that the output will remain in a logic high state (i.e. VO > 2.0 V).

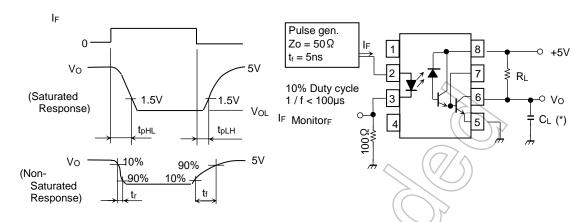
Common mode transient immunity in Logic Low level is the maximum tolerable (negative) dVCM / dt on the trailing edge of the common mode pulse signal, VCM, to assure that the output will remain in a logic low state (i.e. VO < 0.8 V).



+5V

-○ Vo

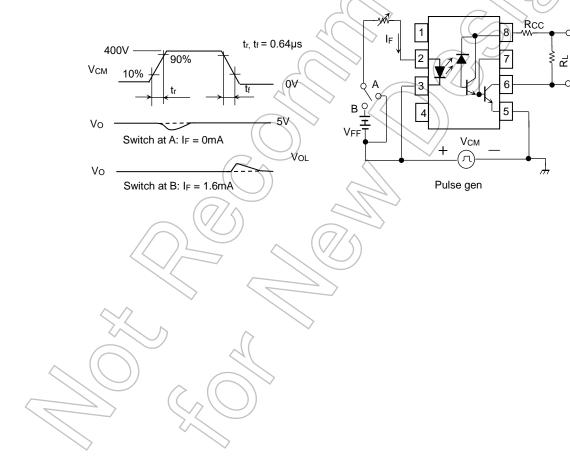
Test Circuit 1.



(*) $C_{\rm L}$ is approximately 15pF which includes probe

and stray wiring capacitance.

Test Circuit 2.





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